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16/C 2002
PA 18-03

500.37149X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: S. MAEDA et al.

Serial No.: 09/294,137

Filed: April 20, 1999

For: DEFECT INSPECTION METHOD AND APPARATUS

RECEIVED

Art Unit: 2621

DEC 18 2002

Examiner: B. Werner

Technology Center 2600

AMENDMENT AFTER FINAL REJECTION

Box AF
Assistant Commissioner for Patents
Washington, D.C. 20231

December 16, 2002

Sir:

In response to the final Office Action of May 13, 2002, and the Office communication of May 24, 2002, and further to the Notice of Appeal of October 15, 2002, please amend the above-identified application as follows.

No additional claim fee is due in connection with the filing of the present amendment.

IN THE CLAIMS

Amend claims 7-8, 15, 22, and 27 as follows:

locally not defined